

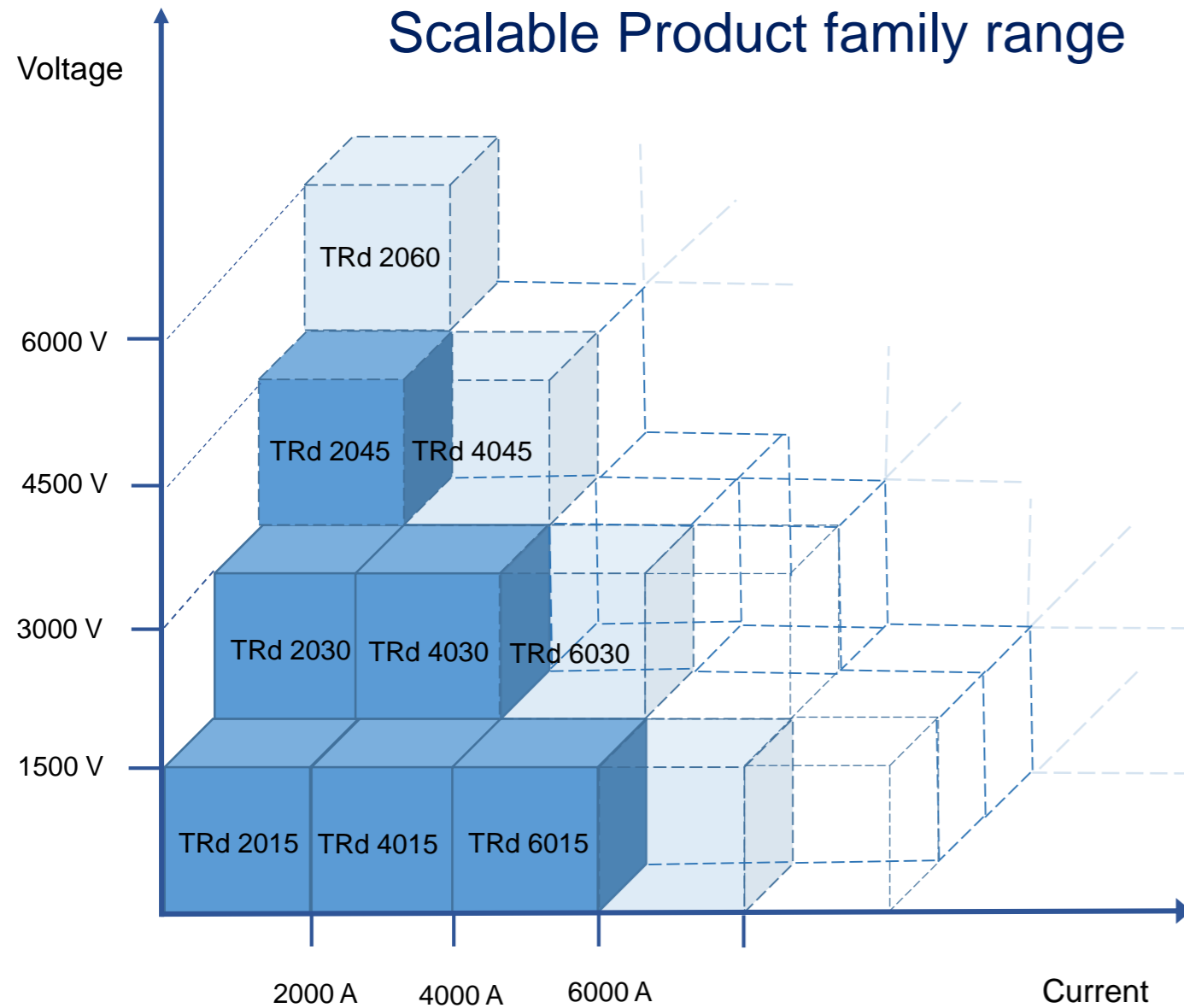


## TRds Product Family



The modular way  
The reference in power semiconductor testing  
[www.lemsys.com](http://www.lemsys.com)

## Scalable Product family range



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LEMSYS partner in China

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# TRds Product Family range : agility and performance from characterization to mass production

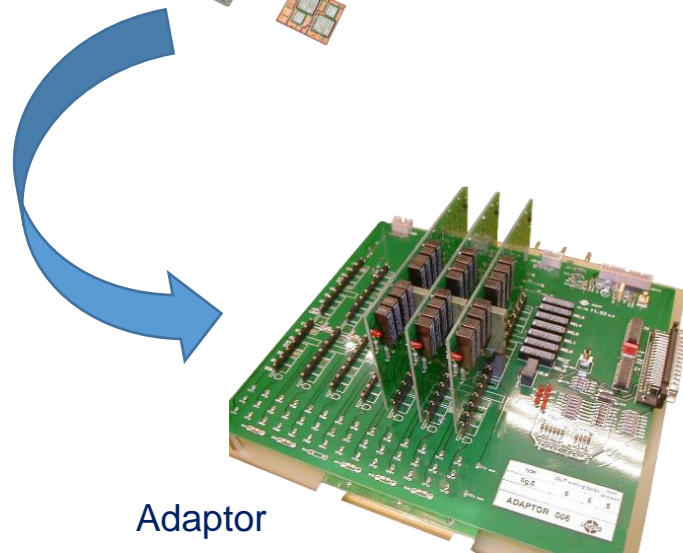
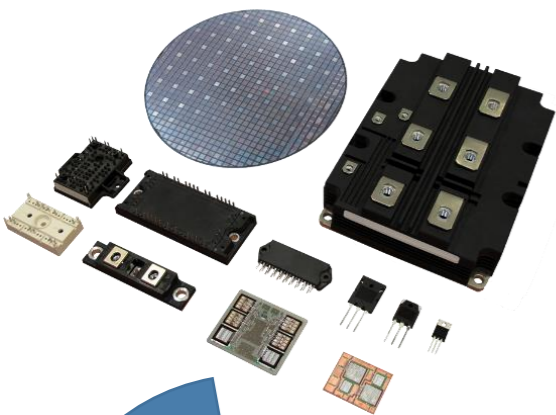
- Building block power modules architecture to enable different configurations
- Flexibility combined with remote diagnostic feature for easy upgrade and maintenance
- Downtime optimization



LEMSYS TRds tester/Manual loading

## What can you test with the TRds product family ?

- Device under test (DUT): IGBT and MOSFET
- Discrete devices to complex power modules
- from 5A to 6000 V (14k for short circuit)
- From 50V to 8000V

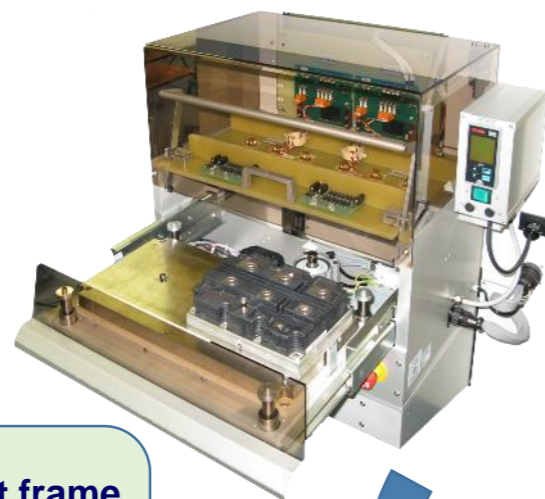


Adaptor

## Step 1

- Place the DUT into a **LEMSYS adaptor** featuring a switching matrix for complex modules.
- Our adaptors are designed to minimize the inductance in dynamic test
- Our adaptors allow a high degree of customization to ensure a perfect fit with the DUT

Test frame



## Step 2

- Insert the adaptor into a **LEMSYS test frame**
- This unit consists of a semi automatic frame
- Available in complete range and incorporating an optional heating system.



LEMSYS TRds tester



Fully LEMSYS automated test line

## TRds family key features

- Designed for IGBT, MOSFET and Diode from single chip to complex power modules
- Complete Dynamic and Static test available as standalone programs as well as combined
- Avalanche and short circuit test available
- IGBT: test fully compliant with IEC 60747-9 edition 2.0
- Diode: test fully compliant test IEC 60747-2 edition 2
- Customizable test options
- Fully compliant with international safety standards
- Fully compatible with Lemsys test frame as well as with any kind of handler.
- Seamless data transfer for quality statistical analysis
- Up to date Graphical User Interface